


<b>Search Notes</b>  	<b>Application/Control No.</b>  10594214	<b>Applicant(s)/Patent Under Reexamination</b>  KATAOKA ET AL.
	<b>Examiner</b>  Cecilia M Jaisle	<b>Art Unit</b>  1624

SEARCHED			
Class	Subclass	Date	Examiner
544	229, 258	11/5/2007	Cecilia Jaisle
544	229, 258	11/9/2008	C. Jaisle

SEARCH NOTES		
Search Notes	Date	Examiner
STN and Inventor Names searched by STIC	11/5/2007	C. Jaisle

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
544	229, 258	11/5/2007	C. Jaisle
544	229, 258	11/9/2008	C. Jaisle

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